



#### N-CHANNEL ENHANCEMENT MODE MOSFET

#### **Product Summary**

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	l <sub>D</sub> max T <sub>A</sub> = +25°C
30V	14mΩ @ VGS = 10V	8.0A
	20mΩ @ VGS = 4.5V	6.7A

#### Description

This new generation MOSFET has been designed to minimize the onstate resistance (RDS(on)) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

#### Applications

- **DC-DC Converters**
- Power management functions

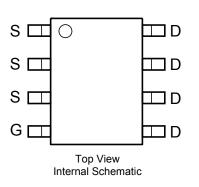
#### Features and Benefitss

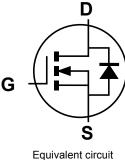
- 14mΩ @ V<sub>GS</sub> = 10V
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

#### **Mechanical Data**

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See Diagram
- Terminals: Finish Matte Tin annealed over Copper lead frame. Solderable per MIL-STD-202, Method 208
- Weight: 0.072 grams (approximate)







## Ordering Information (Note 4)

Part Number	Case	Packaging	
DMN4800LSSL-13	SO-8	2500/Tape & Reel	

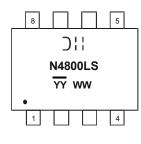
1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. Notes:

2. See http://www.diodes.com/quality/lead free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.

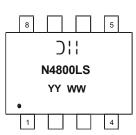
3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

4. For packaging details, go to our website at http://www.diodes.com/products/packages.html

## Marking Information



Chengdu A/T Site



Shanghai A/T Site

⊃¦¦ = Manufacturer's Marking N4800LS = Product Type Marking Code YYWW = Date Code Marking YY or  $\overline{YY}$  = Year (ex: 13 = 2013) WW = Week (01 - 53) YY = Date Code Marking for SAT (Shanghai Assembly/ Test site) YY = Date Code Marking for CAT (Chengdu Assembly/ Test site)



#### Maximum Ratings (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V <sub>DSS</sub>	30	V
Gate-Source Voltage			V <sub>GSS</sub>	±20	V
Drain Current (Note 5) VGS = 10V	,	Γ <sub>A</sub> = +25°C Γ <sub>A</sub> = +70°C	Ι <sub>D</sub>	8.0 6.4	А
Drain Current (Note 5) VGS = 10V	,	Γ <sub>A</sub> = +25°C Γ <sub>A</sub> = +70°C	Ι <sub>D</sub>	6.7 5.3	А
Pulsed Drain Current (Note 6)	·		I <sub>DM</sub>	50	А

# **Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 5)	PD	1.46	W
Thermal Resistance, Junction to Ambient	R <sub>0JA</sub>	86	°C/W
Operating and Storage Temperature Range	T <sub>J,</sub> T <sub>STG</sub>	-55 to +150	°C

# Electrical Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

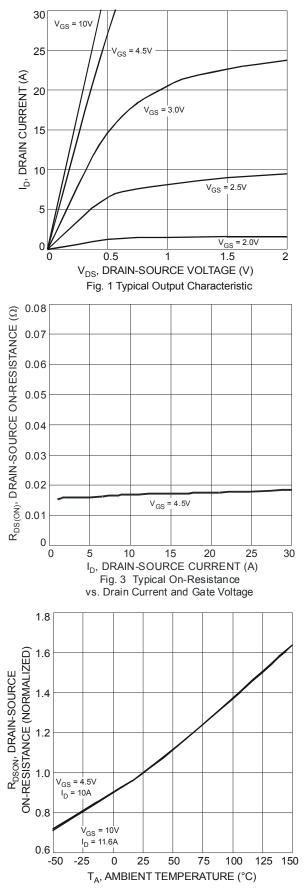
		1			1		
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30			V	$V_{GS} = 0V, I_D = 250 \mu A$	
Zero Gate Voltage Drain Current	IDSS		_	1	μA	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS}$ = ±20V, $V_{DS}$ = 0V	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V <sub>GS(th)</sub>	0.8	1.2	1.6	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
Static Drain-Source On-Resistance			11	14	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 8A	
	R <sub>DS (ON)</sub>		14	20	11122	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 7A	
Forward Transconductance	<b>g</b> fs	_	8	—	S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 8A	
Diode Forward Voltage (Note 7)	V <sub>SD</sub>		0.72	0.94	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS							
Input Capacitance	Ciss		798		pF		
Output Capacitance	Coss		128		pF	−V <sub>DS</sub> = 10V, V <sub>GS</sub> = 0V −f = 1.0MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>		122		pF	1 - 1.00012	
Gate Resistance	R <sub>G</sub>		1.37		Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Total Gate Charge	Qg		8.7			V <sub>GS</sub> = 5V, V <sub>DS</sub> = 15V, I <sub>D</sub> = 9A	
Gate-Source Charge	Q <sub>gs</sub>		1.7		nC		
Gate-Drain Charge	Q <sub>gd</sub>	_	2.4				
Turn-On Delay Time	t <sub>d(on)</sub>	_	5.03			V <sub>DD</sub> = 15V, V <sub>GEN</sub> = 10V, R <sub>L</sub> = 15Ω, R <sub>G</sub> = 6.0Ω, I <sub>D</sub> = 1A	
Rise Time	tr		4.50		]		
Turn-Off Delay Time	t <sub>d(off)</sub>	_	26.33	_	ns		
Fall Time	t <sub>f</sub>	—	8.55		1		

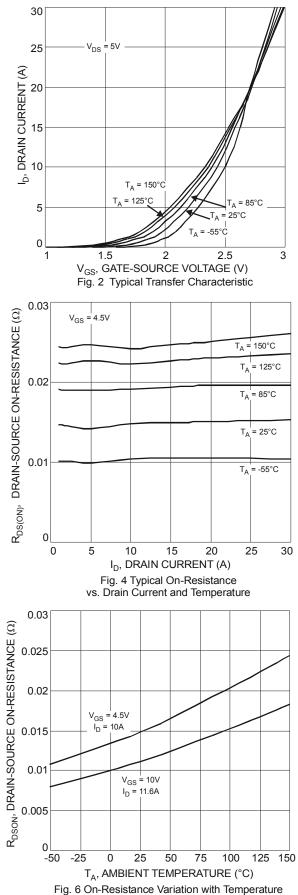
Notes:

5. Device mounted on FR-4 PCB, with minimum recommended pad layout.

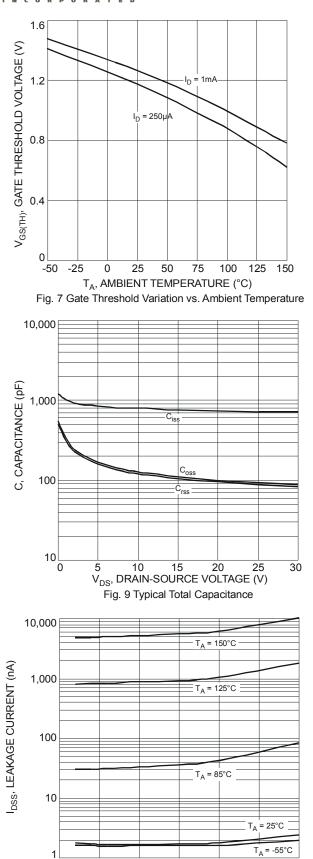
Bevice meaned of PCP, with minimum recommended.
Repetitive rating, pulse width limited by junction temperature.
Short duration pulse test used to minimize self-heating effect.











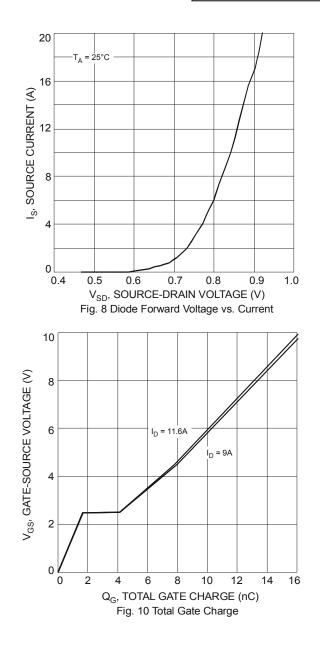
V<sub>DS</sub>, DRAIN-SOURCE VOLTAGE (V) Fig. 11 Typical Leakage Current vs. Drain-Source Voltage

15

20

25

30



0

5

10



Max 1.75

0.20

1.50

0.25

0.5

4.95

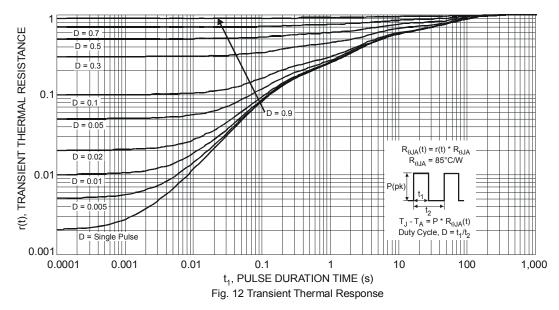
6.10

3.95

0.35

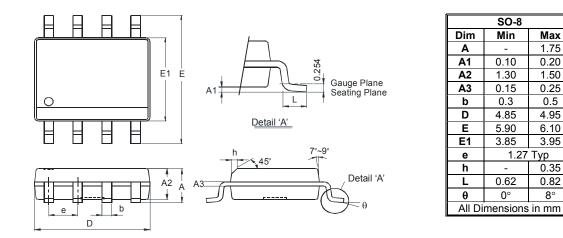
0.82

8°



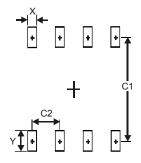
# **Package Outline Dimensions**

Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



## Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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